Sample Results Summary Sheet Please return this form to the Curator for each allocated Sample

Sample ID: RA-QD02-0063

PI: Tomoki Nakamura

Type and date of analysis performed:

XRD Jan/28/2011~ Feb/3/2011 FE-SEM Feb/19/2011~ Feb/28/2011

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

XRD: OI, LPx, PI

FE-SEM: OI

Contaminant phases identified: (Al, SUS, carbon particles, etc.)

N/A

Sample handling:

XRD

Attached to carbon fiber with resin.

FE-SEM

Exposed in atmosphere.

Polished by M cross

C-coated (20 nm)

State of sample pre-analysis:

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded (FE-SEM)

State of sample post-analysis:

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded, C-coated (FE-SEM)

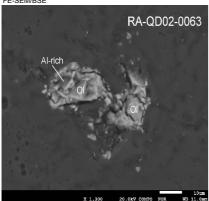
N₂ hold in sample holder.

Analysis data Notes: (summary of the attached analysis data and/or images) See attached sheets.

RA-QD02-0063

Analysis Present status S-XRD (polish) FE-SEM
Putted butt with poor polishing

FE-SEM/BSE



S-XRD

